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LE

- Function and Pinout Compatible With FCT and F Logic
- Reduced V_{OH} (Typically = 3.3 V) Versions of Equivalent FCT Functions
- Edge-Rate Control Circuitry for Significantly Improved Noise Characteristics
- I_{off} Supports Partial-Power-Down Mode Operation
- ESD Protection Exceeds JESD 22
 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)
- Matched Rise and Fall Times
- Fully Compatible With TTL Input and Output Logic Levels
- 3-State Outputs
- CY54FCT573T
 - 32-mA Output Sink Current
 - 12-mA Output Source Current
- CY74FCT573T
 - 64-mA Output Sink Current
 - 32-mA Output Source Current

description

The 'FCT573T devices consist of eight latches with 3-state outputs for bus-organized applications. When the latch-enable (LE) input is high, the flip-flops appear transparent to the data. Data that meets the required setup times are latched when LE transitions from high to low. Data appears on the bus when the output-enable (\overline{OE}) input is low. When \overline{OE} is high, the bus output is in the high-impedance state. In this mode, data can be entered into the latches. The 'FCT573T devices are identical to the 'FCT373T devices, except for the flow-through pinout of the 'FCT573T, which simplifies board design.

These devices are fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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CY54FC15/31 D PACKAGE CY74FCT573T P, Q, OR SO PACKAGE (TOP VIEW)											
OE [1	20	$ \begin{array}{c} V_{CC}\\O_0\\O_1\\O_2\\O_3\\O_4\end{array} $								
D ₀ [2	19									
D ₁ [3	18									
D ₂ [4	17									
D ₃ [5	16									
D ₄ [6	15									

D₅ 7

D₆ [8

D₇ 9

GND 10

CY54FCT573T, CY74FCT573T 8-BIT LATCHES WITH 3-STATE OUTPUTS SCCS068 - OCTOBER 2001

TA	PAC	KAGE [†]	SPEED (ns)	ORDERABLE PART NUMBER	TOP-SIDE MARKING						
	QSOP – Q	FCT573C									
	SOIC – SO	Tube	4.7	CY74FCT573CTSOC	FCT573C						
	5010 - 50	Tape and reel	4.7	CY74FCT573CTSOCT	FC1573C						
	DIP – P	Tube	5.2	CY74FCT573ATPC	CY74FCT573ATPC						
-40°C to 85°C	QSOP – Q	Tape and reel	5.2	CY74FCT573ATQCT	FCT573A						
-40 C 10 85 C		SOIC – SO		5.2	CY74FCT573ATSOC	FCT573A					
	3010 - 30	Tape and reel	5.2	CY74FCT573ATSOCT	FC1575A						
	QSOP – Q	Tape and reel	8	CY74FCT573TQCT	FCT573						
	SOIC – SO	Tube	8	CY74FCT573TSOC	FCT573						
	3010 - 30	Tape and reel	8	CY74FCT573TSOCT	FU1073						
–55°C to 125°C	CDIP – D	Tube	8.5	CY54FCT573ATLMB							

ORDERING INFORMATION

[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE

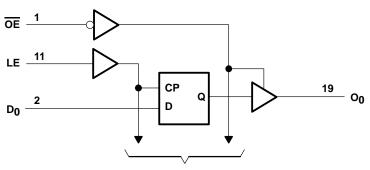
	INPUTS		OUTPUT
OE	LE	D	0
L	Н	Н	Н
L	Н	L	L
L	L	Х	Q ₀
н	Х	Х	Z

H = High logic level, L = Low logic level,

X = Don't care, Z = High-impedance state, Q_n = Previous state of flip flops (Q_{n-1})

 $\alpha_n = \text{Previous state of hip hops} (\alpha_{n-1})$

logic diagram (positive logic)



To Seven Other Channels



CY54FCT573T, CY74FCT573T **8-BIT LATCHES** WITH 3-STATE OUTPUTS

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absolute maximum rating over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range to ground potential		0.5	V to 7 V
DC input voltage range		0.5	V to 7 V
DC output voltage range		0.5	V to 7 V $$
DC output current (maximum sink current/pin)			120 mA
Package thermal impedance, θ_{JA} (see Note 1):	P package		69°C/W
	Q package		68°C/W
	SO package		58°C/W
Ambient temperature range with power applied,	, T _A	–65°C ⁻	to 135°C
Storage temperature range, T _{stg}		–65°C	to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions (see Note 2)

		CY54FCT573T			CY	4FCT57	'3T	UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
ЮН	High-level output current			-12			-32	mA
IOL	Low-level output current			32			64	mA
Т _А	Operating free-air temperature	-55		125	-40		85	°C

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.



CY54FCT573T, CY74FCT573T **8-BIT LATCHES** WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DAD AMETER	TERT CONDITIONS	CY	54FCT57	73T	CY	74FCT57	′3T						
PARAMETER	TEST CONDITIONS	MIN	түр†	MAX	MIN	түр†	MAX	UNIT					
Maria	V _{CC} = 4.5 V, I _{IN} = -18 mA		-0.7	-1.2				v					
VIK	$V_{CC} = 4.75 \text{ V}, I_{IN} = -18 \text{ mA}$					-0.7	-1.2	v					
	$V_{CC} = 4.5 \text{ V}, \qquad I_{OH} = -12 \text{ mA}$	2.4	3.3										
Vон	$I_{OH} = -32 \text{ mA}$				2			V					
	$V_{CC} = 4.75 \text{ V}$ $I_{OH} = -15 \text{ mA}$				2.4	3.3							
Ve	$V_{CC} = 4.5 \text{ V}, \qquad I_{OL} = 32 \text{ mA}$		0.3	0.55				v					
VOL	$V_{CC} = 4.75 \text{ V}, I_{OL} = 64 \text{ mA}$					0.3	0.55	v					
V _{hys}	All inputs		0.2			0.2		V					
1.	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} = V_{CC}$			5				μA					
łı	$V_{CC} = 5.25 \text{ V}, V_{IN} = V_{CC}$						5	μA					
łІН	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} = 2.7 \text{ V}$			±1				μA					
ЧН	$V_{CC} = 5.25 \text{ V}, V_{IN} = 2.7 \text{ V}$						±1	μА					
١ _{IL}	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} = 0.5 \text{ V}$			±1				μA					
	$V_{CC} = 5.25 \text{ V}, V_{IN} = 0.5 \text{ V}$						±1	μA					
1	V _{CC} = 5.5 V, V _{OUT} = 2.7 V			10				μA					
IOZH	V _{CC} = 5.25 V, V _{OUT} = 2.7 V						10	μη					
	V _{CC} = 5.5 V, V _{OUT} = 0.5 V			-10				μA					
IOZL	V _{CC} = 5.25 V, V _{OUT} = 0.5 V						μ						
le et	V _{CC} = 5.5 V, V _{OUT} = 0 V	-60	-120	-225				~					
IOS‡	V _{CC} = 5.25 V, V _{OUT} = 0 V				-60	-120	-225	mA					
loff	V _{CC} = 0 V, V _{OUT} = 4.5 V			±1			±1	μA					
	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} \le 0.2 \text{ V}, \qquad \qquad V_{IN} \ge V_{CC} - 0.2 \text{ V}.$	2 V	0.1	0.2				m 4					
ICC	$V_{CC} = 5.25 \text{ V}, \qquad V_{IN} \le 0.2 \text{ V}, \qquad \qquad V_{IN} \ge V_{CC} - 0.2 \text{ V}.$	2 V				0.1	0.2	mA					
	$V_{CC} = 5.5 \text{ V}, \text{ V}_{IN} = 3.4 \text{ V}$ $\text{$\%$}, \text{$f_1 = 0$, Outputs open}$		0.5	2				mA					
⊅ICC	V_{CC} = 5.25 V, V_{IN} = 3.4 V§, f ₁ = 0, Outputs open					0.5	2	IIIA					
ICCD¶	V_{CC} = 5.5 V, Outputs open, One input switching at 50% duty cycle, \overline{OE} = GND, $V_{IN} \le 0.2$ V or $V_{IN} \ge V_{CC} - 0.2$ V		0.06	0.12				mA					
	$V_{CC} = 5.25$ V, Outputs open, One input switching at 50% duty cycle, $\overline{OE} = GND$, $V_{IN} \le 0.2$ V or $V_{IN} \ge V_{CC} - 0.2$ V					0.06	0.12	МН					

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡] Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, IOS tests should be performed last.

§ Per TTL-driven input (V_{IN} = 3.4 V); all other inputs at V_{CC} or GND

¶ This parameter is derived for use in total power-supply calculations.



CY54FCT573T, CY74FCT573T 8-BIT LATCHES WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted) (continued)

		TEST CONDITIONS				73T	CY	74FCT57	73T	UNIT
PARAMETER		TEST CONDITION	MIN	түр†	MAX	MIN	түр†	MAX	UNIT	
	V _{CC} = 5.5 V,	One bit switching at f ₁ = 10 MHz	$\begin{array}{l} V_{IN} \leq 0.2 \ V \ or \\ V_{IN} \geq V_{CC} - 0.2 \ V \end{array}$		0.7	1.4				
	Outputs open,	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		1	2.4				
	$\overline{OE} = GND,$ LE = V _{CC}	Eight bits switching at $f_1 = 2.5$ MHz	$V_{IN} \leq 0.2 \text{ V or} \\ V_{IN} \geq V_{CC} - 0.2 \text{ V}$		1.3	2.6				
. #		at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		3.3	10.6ll				mA
'C#	V _{CC} = 5.25 V,		$\begin{array}{l} V_{IN} \leq 0.2 \ V \ or \\ V_{IN} \geq V_{CC} - 0.2 \ V \end{array} \end{array} \label{eq:VIN}$					0.7	1.4	ША
	Outputs open,		$V_{IN} = 3.4 \text{ V or GND}$					1	2.4	
	OE = GND, LE = V _{CC}		$\begin{array}{l} V_{IN} \leq 0.2 \ V \ or \\ V_{IN} \geq V_{CC} - 0.2 \ V \end{array} \end{array} \label{eq:VIN}$					1.3	2.6	
		at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$					3.3	10.6ll	
Ci					6	10		6	10	pF
Co					8	12		8	12	pF

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}C$.

[#] IC = ICC + Δ ICC × D_H × N_T + I_{CCD} (f₀/2 + f₁ × N₁)

Where:

= Total supply current IC

ICC = Power-supply current with CMOS input levels

 ΔI_{CC} = Power-supply current for a TTL high input (VIN = 3.4 V)

 D_H = Duty cycle for TTL inputs high NT = Number of TTL inputs at D_H

I_{CCD} = Dynamic current caused by an input transition pair (HLH or LHL)

= Clock frequency for registered devices, otherwise zero fo

= Input signal frequency f1

N₁ = Number of inputs changing at f1

All currents are in milliamperes and all frequencies are in megahertz.

|| Values for these conditions are examples of the I_{CC} formula.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		CY54FC	T573T	CY54FCT	UNIT	
		MIN	MAX	MIN	MAX	
tw	Pulse duration, LE high	6		6		ns
t _{su}	Setup time, data before LE [↑]	2		2		ns
th	Hold time, data after LE↑	1.5		1.5		ns

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		CY74FC	T573T	CY74FCT	573AT	CY74FCT	573CT	UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
tw	Pulse duration, LE high	6		5		5		ns
t _{su}	Setup time, data before LE↑	2		2		2		ns
th	Hold time, data after LE↑	1.5		1.5		1.5		ns



CY54FCT573T, CY74FCT573T 8-BIT LATCHES WITH 3-STATE OUTPUTS SCCS068 - OCTOBER 2001

switching characteristics over operating free-air temperature range (see Figure 1)

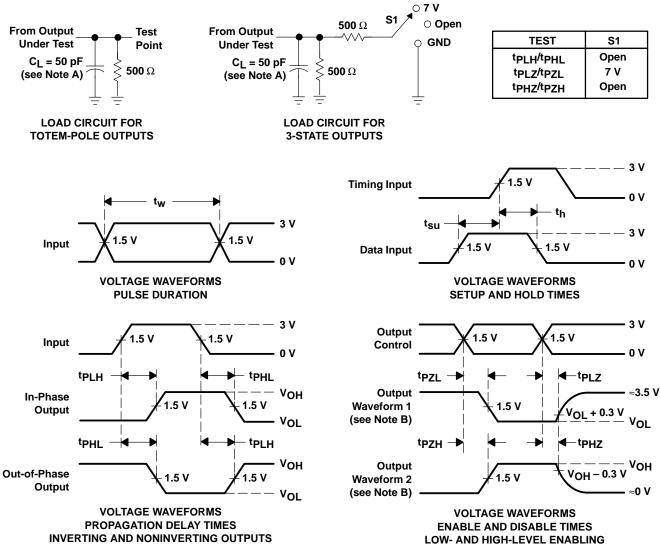
PARAMETER	FROM	то	CY54FCT	573AT	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	UNIT	
^t PLH	D	0	1.5	5.6	ns	
^t PHL	J	0	1.5	5.6	115	
^t PLH	LE	0	2	9.8	ns	
^t PHL	EL .	0	2	9.8		
^t PZH	OE	0	1.5	7.5	ns	
^t PZL	ÖE	0	1.5	7.5	115	
^t PHZ	OE	0	1.5	6.5	ne	
^t PLZ	UE UE	5	1.5	6.5	ns	

switching characteristics over operating free-air temperature range (see Figure 1)

PARAMETER	FROM	то	CY74FC	CY74FCT573T		CY74FCT573AT		CY74FCT573CT	
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	D	0	1.5	8	1.5	5.2	1.5	4.7	ns
^t PHL	D	0	1.5	8	1.5	5.2	1.5	4.7	115
^t PLH	LE	0	2	13	2	8.5	2	5.5	ns
^t PHL	LL		2	13	2	8.5	2	5.5	115
^t PZH	OE	0	1.5	12	1.5	6.5	1.5	5.5	
^t PZL	OE	0	1.5	12	1.5	6.5	1.5	5.5	ns
^t PHZ	OE	DE O	1.5	7.5	1.5	5.5	1.5	5	ns
^t PLZ	UE	0	1.5	7.5	1.5	5.5	1.5	5	115



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. C_L includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms





PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
5962-9223801MRA	ACTIVE	CDIP	J	20	1	Non-RoHS & Non-Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9223801MR A	Samples
5962-9223802M2A	ACTIVE	LCCC	FK	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962- 9223802M2A CY54FCT 573ATLMB	Samples
CY54FCT573ATLMB	ACTIVE	LCCC	FK	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962- 9223802M2A CY54FCT 573ATLMB	Samples
CY74FCT573ATPC	ACTIVE	PDIP	N	20	20	RoHS & Non-Green	NIPDAU	N / A for Pkg Type	-40 to 85	CY74FCT573ATPC	Samples
CY74FCT573ATQCT	ACTIVE	SSOP	DBQ	20	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT573A	Samples
CY74FCT573ATSOC	ACTIVE	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT573A	Samples
CY74FCT573ATSOCT	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT573A	Samples
CY74FCT573CTQCT	ACTIVE	SSOP	DBQ	20	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT573C	Samples
CY74FCT573CTSOC	ACTIVE	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT573C	Samples
CY74FCT573TQCT	ACTIVE	SSOP	DBQ	20	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT573	Samples
CY74FCT573TSOC	ACTIVE	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT573	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ **RoHS**: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

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PACKAGE OPTION ADDENDUM

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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*All dimensions are nominal

STRUMENTS

TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CY74FCT573ATQCT	SSOP	DBQ	20	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT573ATSOCT	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CY74FCT573CTQCT	SSOP	DBQ	20	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT573TQCT	SSOP	DBQ	20	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1



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PACKAGE MATERIALS INFORMATION

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CY74FCT573ATQCT	SSOP	DBQ	20	2500	356.0	356.0	35.0
CY74FCT573ATSOCT	SOIC	DW	20	2000	367.0	367.0	45.0
CY74FCT573CTQCT	SSOP	DBQ	20	2500	356.0	356.0	35.0
CY74FCT573TQCT	SSOP	DBQ	20	2500	356.0	356.0	35.0

TEXAS INSTRUMENTS

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TUBE



- B - Alignment groove width

*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	Τ (μm)	B (mm)
5962-9223802M2A	FK	LCCC	20	1	506.98	12.06	2030	NA
CY54FCT573ATLMB	FK	LCCC	20	1	506.98	12.06	2030	NA
CY74FCT573ATPC	N	PDIP	20	20	506	13.97	11230	4.32
CY74FCT573ATSOC	DW	SOIC	20	25	507	12.83	5080	6.6
CY74FCT573CTSOC	DW	SOIC	20	25	507	12.83	5080	6.6
CY74FCT573TSOC	DW	SOIC	20	25	507	12.83	5080	6.6

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